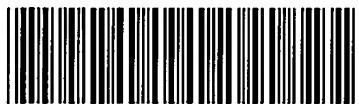


**Search Notes****Application/Control No.**

10/696,357

**Examiner**

Sun J. Lin

**Applicant(s)/Patent under Reexamination**

YOUNG ET AL.

**Art Unit**

2825

**SEARCHED**

Class	Subclass	Date	Examiner
716	12	1/6/2006	JSL
716	13	1/6/2006	JSL
716	14	1/6/2006	JSL
716	16	1/6/2006	JSL
716	17	1/6/2006	JSL

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST [USPAT;US- PGPUB;EPO;JPO;DERWENT;IBM_T DB]	1/6/2006	JSL
IEEE	1/6/2006	JSL

**INTERFERENCE SEARCHED**

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716	12	1/6/2006	JSL
716	13,14	1/6/2006	JSL
716	16,17	1/6/2006	JSL